## Characterization of Shape-Preserving Diatom Displacement Reactions using High Temperature X-ray Diffraction

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Shape preserving displacement reactions of the type  $2Mg(s) + SiO_2(s) > 2MgO(s) + {Si}$  and  $TiF_4(g) + SiO_2(s) > TiO_2(s) + SiF_4(g)$ where the SiO<sub>2</sub> is in the form of diatoms were studied using high temperature x-ray diffraction (HTXRD) with the samples sealed inside graphite reaction vessels. Enclosure of the sample within the graphite cell allows for containment of the vapor formed during the reaction (Mg(g) and TiF<sub>4</sub>(g) respectively). Reactions of this type allow for complete conversion of the complex-shaped SiO<sub>2</sub> diatom frustule to alternate chemistries (such as MgO and TiO<sub>2</sub>) with no loss of structural features. HTXRD measurements show complete conversion of SiO<sub>2</sub> to MgO after approximately one hour at 700°C, and after 45 minutes for SiO<sub>2</sub> to TiO<sub>2</sub> at 300°C. The kinetics of both reactions were also probed using isothermal measurements.

Keywords: diatoms, shape preserving, displacement reactions